

**Search Notes**

Application/Control No.

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Examiner

David E. Bochna

Applicant(s)/Patent under  
Reexamination

KURIHARA ET AL.

Art Unit

3679

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated the previous search	6/21/2005	DB